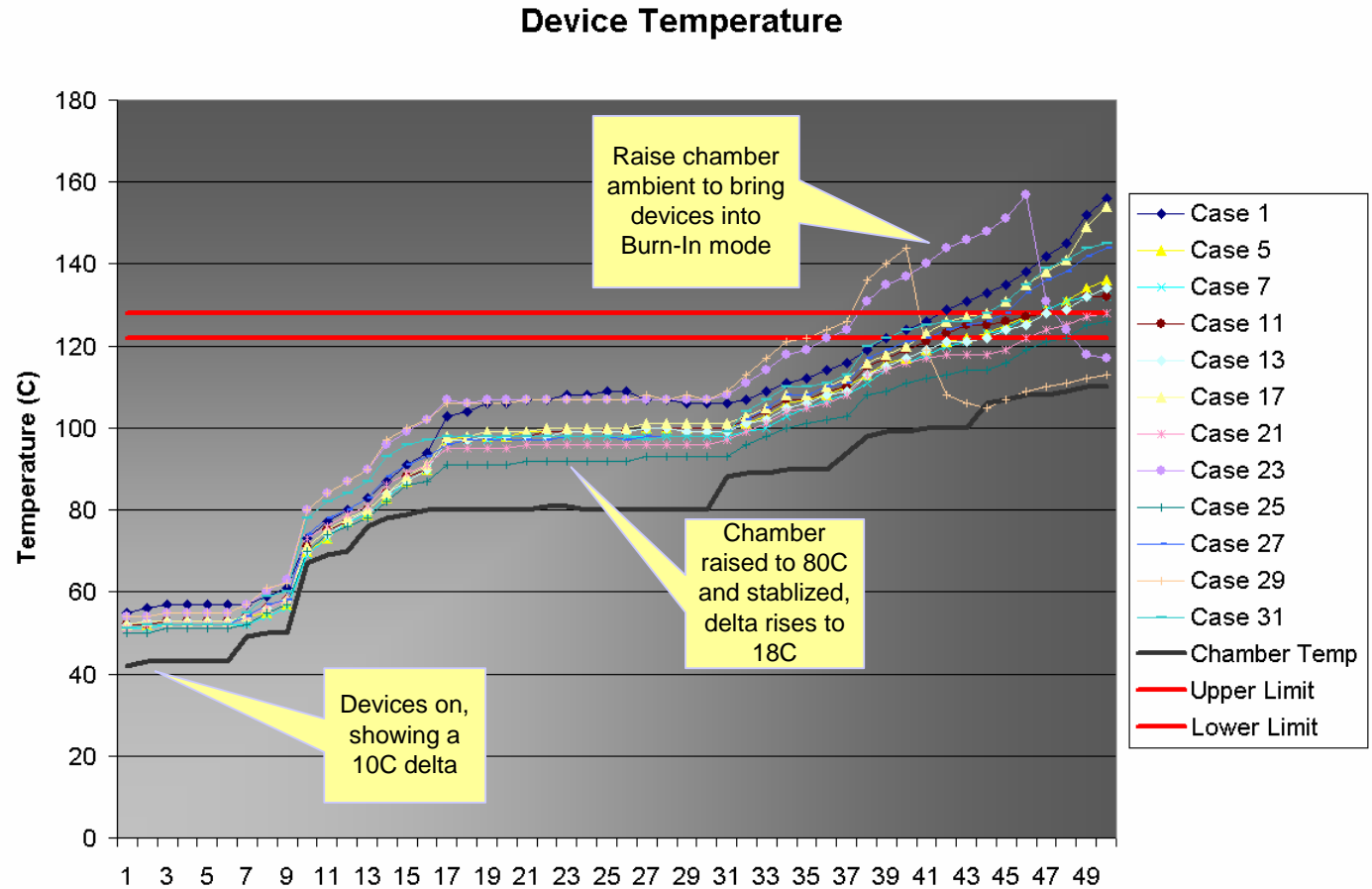


HTOL Testing of low geometry high power VLSI devices



The challenge.



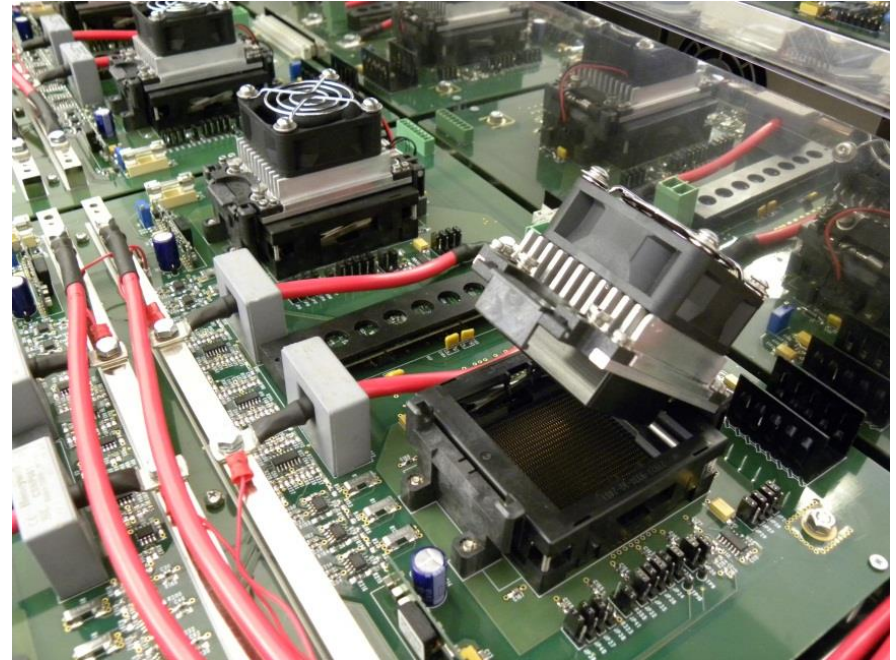
Picture courtesy of Sensata

HTOL Testing of low geometry high power VLSI devices



High Power HTOL Application

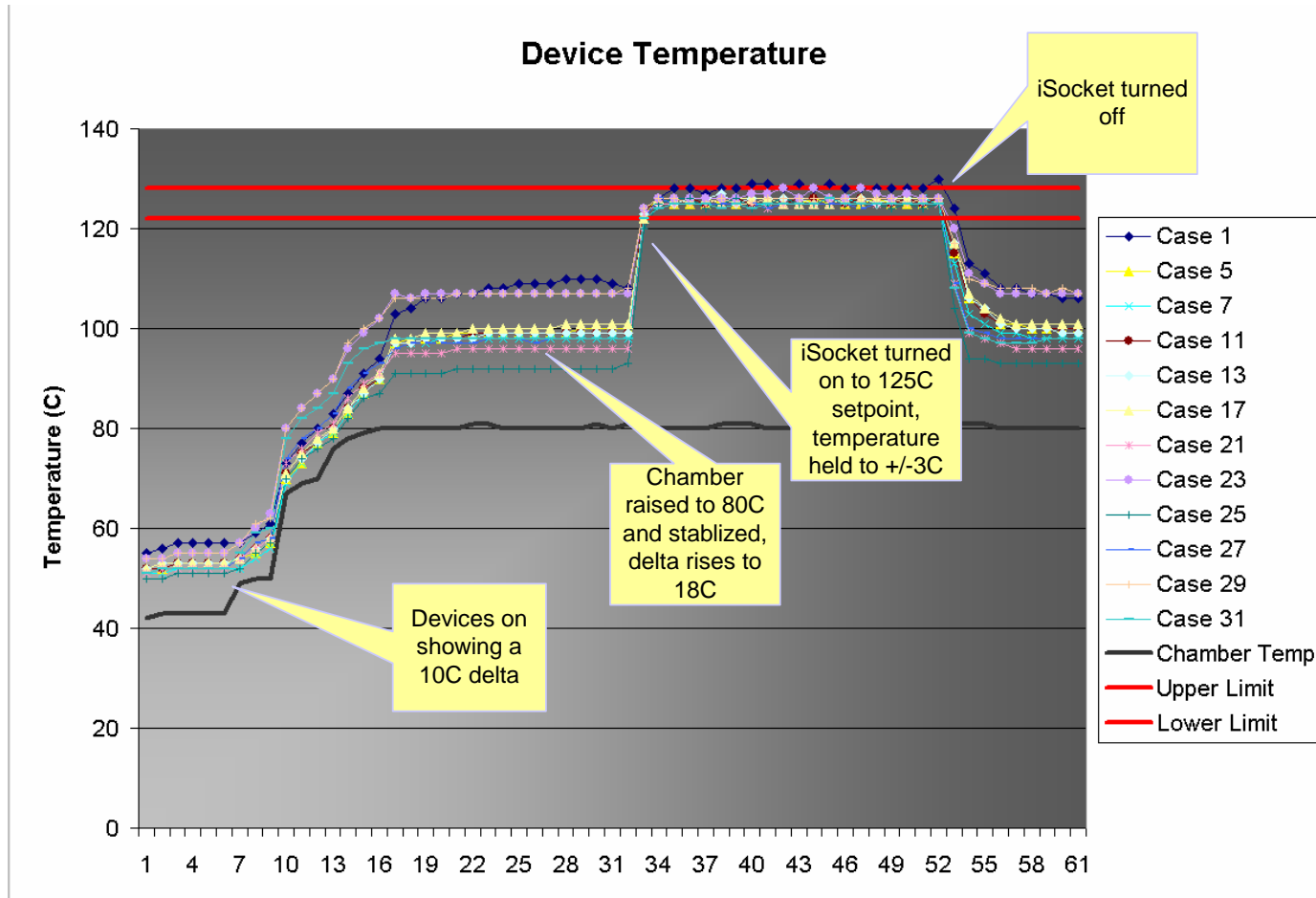
- ▶ Not possible to perform in a conventional HTOL Chamber
- ▶ Requires individual temperature control per DUT
- ▶ Provided by Reltech 8000 series HTOL series incorporating iSocket™ technology



HTOL Testing of low geometry high power VLSI devices



The solution – what iSocket achieves:



Picture courtesy of Sensata

Reltech 8000 series iSocket™ – High Power DUT – HTOL System

8014 HTOL System Features

- iSocket™ Technology
- Open Rack – Room Temperature (RTBI) non chamber design
- High Power DUT Capability – 0–65W
- Individual DUT Temperature Measurement & Control
- DUT Monitoring with Auto shut down
- 28 BIB capacity – 14 trays
2 BIB's per tray
- Multi DUT type HTOL Testing
- Remote System & HTOL Monitoring – Customer access via VPN



Reltech 8000 series iSocket™ – High Power DUT – HTOL System



Reltech 8000 series iSocket™ – High Power DUT – HTOL System

New challenges – new developments:

- On BIB Vector Generator



Picture courtesy of Marvel Israel

Performance	
Vector Channels:	40
Memory Depth:	64M
Max Vector Frequency (recommended):	20MHz
DUT Monitor Channels	60
Analogue Channels	4
Other special Channels	13